FCC ID: 2A72B-BC02

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]· $[\sqrt{f(GHZ)}] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculatio n	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	6.92	4.92	6.5±1	7.5	5.62	<5	1.74308	3.00	YES
	2.441	7.1	5.13	6.5±1	7.5	5.62	<5	1.75717	3.00	YES
	2.480	6.54	4.51	6.5±1	7.5	5.62	<5	1.77115	3.00	YES
π/4- DQPSK	2.402	6.93	4.93	6.5±1	7.5	5.62	<5	1.74308	3.00	YES
	2.441	7.1	5.13	6.5±1	7.5	5.62	<5	1.75717	3.00	YES
	2.480	6.54	4.51	6.5±1	7.5	5.62	<5	1.77115	3.00	YES
8-DQPSK	2.402	6.94	4.94	6.5±1	7.5	5.62	<5	1.74308	3.00	YES
	2.441	7.11	5.14	6.5±1	7.5	5.62	<5	1.75717	3.00	YES
	2.480	6.54	4.51	6.5±1	7.5	5.62	<5	1.77115	3.00	YES
BLE 1M	2.402	4.88	3.08	4±1	5	3.16	<5	0.98020	3.00	YES
	2.44	4.98	3.15	4±1	5	3.16	<5	0.98793	3.00	YES
	2.480	4.39	2.75	4±1	5	3.16	<5	0.99599	3.00	YES
BLE 2M	2.402	4.79	3.01	4±1	5	3.16	<5	0.98020	3.00	YES
	2.44	4.88	3.08	4±1	5	3.16	<5	0.98793	3.00	YES
	2.480	4.25	2.66	4±1	5	3.16	<5	0.99599	3.00	YES

Conclusion:

For the max result : $1.77115 \le 3.0$ for 1g SAR, SAR is not required.

Signature: Date: 2023-03-02

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